

74F30 8-Input NAND Gate

General Description

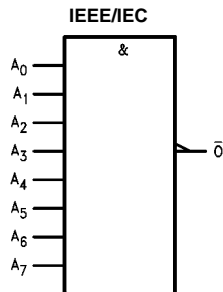
This device contains a single gate, which performs the logic NAND function.

Ordering Code:

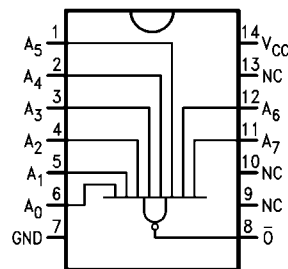
| Order Number | Package Number | Package Description |
|--------------|----------------|---|
| 74F30SC | M14A | 14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow |
| 74F30SJ | M14D | 14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide |
| 74F30PC | N14A | 14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide |

Devices also available in Tape and Reel. Specify by appending the letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Unit Loading/Fan Out

| Pin Names | Description | U.L. HIGH/LOW | Input I_{IH}/I_{IL} Output I_{OH}/I_{OL} |
|-----------|-------------|------------------|---|
| A_0-A_7 | Inputs | 1.0/1.0 | 20 μ A/-0.6 mA |
| \bar{O} | Output | 50/33.3 | -1 mA/20 mA |

Function Table

| Inputs | | | | | | | | Output |
|--------|-------|-------|-------|-------|-------|-------|-------|-----------|
| A_0 | A_1 | A_2 | A_3 | A_4 | A_5 | A_6 | A_7 | \bar{O} |
| L | X | X | X | X | X | X | X | H |
| X | L | X | X | X | X | X | X | H |
| X | X | L | X | X | X | X | X | H |
| X | X | X | L | X | X | X | X | H |
| X | X | X | X | L | X | X | X | H |
| X | X | X | X | X | L | X | X | H |
| X | X | X | X | X | X | L | X | H |
| X | X | X | X | X | X | X | L | H |
| H | H | H | H | H | H | H | H | L |

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Absolute Maximum Ratings(Note 1)

| | |
|--|--------------------------------------|
| Storage Temperature | −65°C to +150°C |
| Ambient Temperature under Bias | −55°C to +125°C |
| Junction Temperature under Bias | −55°C to +150°C |
| V _{CC} Pin Potential to Ground Pin | −0.5V to +7.0V |
| Input Voltage (Note 2) | −0.5V to +7.0V |
| Input Current (Note 2) | −30 mA to +5.0 mA |
| Voltage Applied to Output in HIGH State (with V _{CC} = 0V) | |
| Standard Output | −0.5V to V _{CC} |
| 3-STATE Output | −0.5V to +5.5V |
| Current Applied to Output in LOW State (Max) | twice the rated I _{OL} (mA) |

Recommended Operating Conditions

| | |
|------------------------------|----------------|
| Free Air Ambient Temperature | 0°C to +70°C |
| Supply Voltage | +4.5V to +5.5V |

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

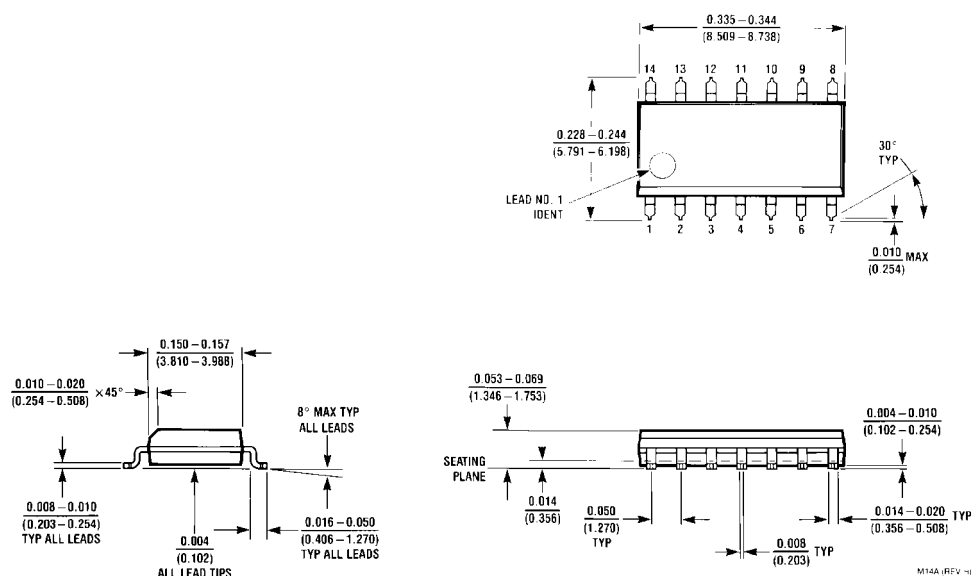
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

| Symbol | Parameter | Min | Typ | Max | Units | V _{CC} | Conditions |
|------------------|-----------------------------------|---|------------|------|-------|-----------------|--|
| V _{IH} | Input HIGH Voltage | 2.0 | | | V | | Recognized as a HIGH Signal |
| V _{IL} | Input LOW Voltage | | | 0.8 | V | | Recognized as a LOW Signal |
| V _{CD} | Input Clamp Diode Voltage | | | −1.2 | V | Min | I _{IN} = −18 mA |
| V _{OH} | Output HIGH Voltage | 10% V _{CC} 5% V _{CC} | 2.5 2.7 | | V | Min | I _{OH} = −1 mA I _{OH} = −1 mA |
| V _{OL} | Output LOW Voltage | 10% V _{CC} | | 0.5 | V | Min | I _{OL} = 20 mA |
| I _{IH} | Input HIGH Current | | | 5.0 | μA | Max | V _{IN} = 2.7V |
| I _{BVI} | Input HIGH Current Breakdown Test | | | 7.0 | μA | Max | V _{IN} = 7.0V |
| I _{CEX} | Output HIGH Leakage Current | | | 50 | μA | Max | V _{OUT} = V _{CC} |
| V _{ID} | Input Leakage Test | 4.75 | | | V | 0.0 | I _{ID} = 1.9 μA All Other Pins Grounded |
| I _{OD} | Output Leakage Circuit Current | | | 3.75 | μA | 0.0 | V _{IOD} = 150 mV All Other Pins Grounded |
| I _{IL} | Input LOW Current | | | −0.6 | mA | Max | V _{IN} = 0.5V |
| I _{OS} | Output Short-Circuit Current | −60 | | −150 | mA | Max | V _{OUT} = 0V |
| I _{CCH} | Power Supply Current | | 0.5 | 1.5 | mA | Max | V _O = HIGH |
| I _{CCL} | Power Supply Current | | | 4.5 | mA | Max | V _O = LOW |

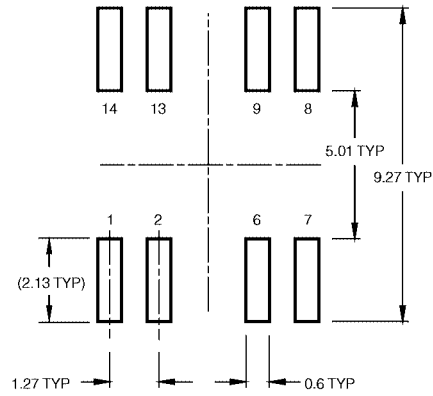
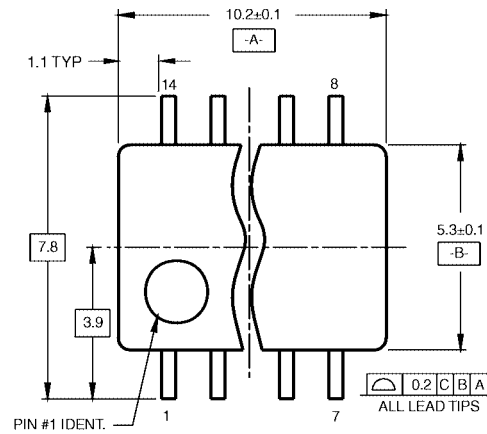
AC Electrical Characteristics

| Symbol | Parameter | T _A = +25°C V _{CC} = +5.0V C _L = 50 pF | | | T _A = 0°C to +70°C V _{CC} = +5.0V C _L = 50 pF | | Units |
|------------------|-----------------------------|---|-----|-----|--|-----|-------|
| | | Min | Typ | Max | Min | Max | |
| t _{PLH} | Propagation Delay | 1.0 | 3.7 | 5.0 | 1.0 | 5.5 | ns |
| t _{PHL} | A _n to \bar{O} | 1.5 | 2.8 | 5.0 | 1.5 | 5.5 | |

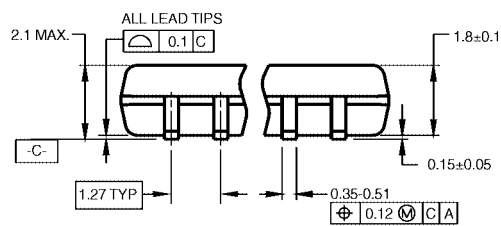


**14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
Package Number M14A**

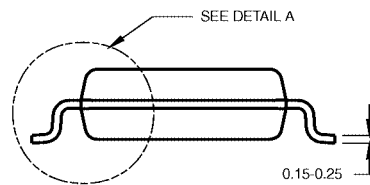
Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



LAND PATTERN RECOMMENDATION



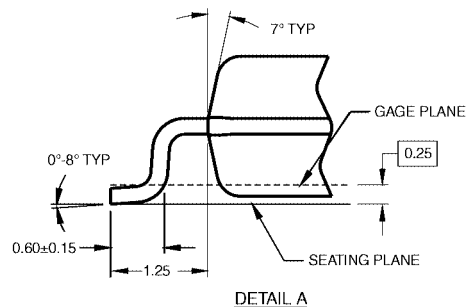
DIMENSIONS ARE IN MILLIMETERS



NOTES:

- A. CONFORMS TO EIAJ EDR-7320 REGISTRATION, ESTABLISHED IN DECEMBER, 1998.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

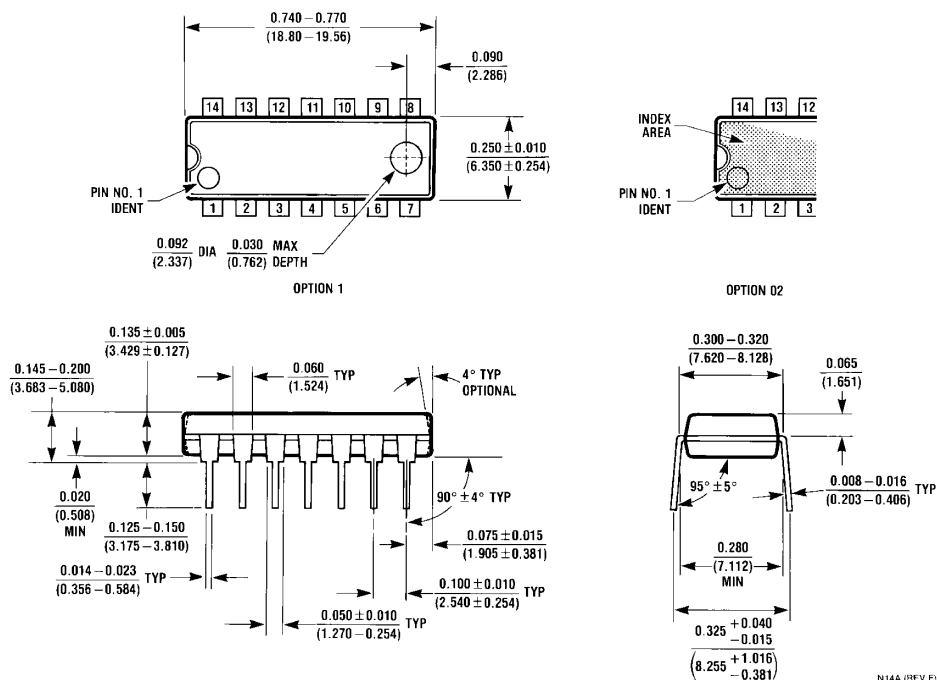
M14DRevB1



DETAIL A

**14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M14D**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
Package Number N14A**

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